





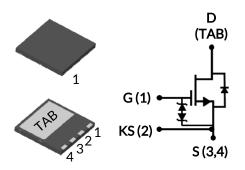








UF3SC065040D8S



Part Number	Package	Marking
UF3SC065040D8S	DFN8X8-4L	UF3SC065040D8S









$650V-45m\Omega$ SiC FET

Rev. B, January 2020

Description

This SiC FET device is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows for a true "drop-in replacement" to Si IGBTs, Si FETs, SiC MOSFETs or Si superjunction devices. Available in the DFN8X8-4L package, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads , and any application requiring standard gate drive.

Features

- Typical on-resistance R_{DS(on),typ} of 45mΩ
- Maximum operating temperature of 150°C
- Excellent reverse recovery
- Low gate charge
- Low intrinsic capacitance
- ESD protected, HBM class 2
- DFN8X8-4L package for faster switching, clean gate waveforms

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating













Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		650	V
Gate-source voltage	V_{GS}	DC	-25 to +25	V
Continuous drain current ¹	I _D	T _C < 120°C	18	А
Pulsed drain current ²	I _{DM}	T _C = 25°C	110	Α
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =3.19A	76	mJ
Power dissipation	P _{tot}	T _C = 25°C	125	W
Maximum junction temperature	$T_{J,max}$		150	°C
Operating and storage temperature	T_J,T_STG		-55 to 150	°C
Reflow soldering temperature	T_{solder}	reflow MSL 3	260	°C

- 1. Limited by bondwires
- 2. Pulse width t_p limited by $T_{J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
			Min	Тур	Max	Offics
Thermal resistance, junction-to-case	$R_{ heta$ JC			0.8	1	°C/W













Electrical Characteristics ($T_J = +25$ °C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions		Units		
			Min	Тур	Max	Offics
Drain-source breakdown voltage	BV _{DS}	V_{GS} =0V, I_D =1mA	650			V
Total drain leakage current	l	V _{DS} =650V, V _{GS} =0V, T _J =25°C		0.7	150	- μΑ
	I _{DSS}	V _{DS} =650V, V _{GS} =0V, T _J =150°C		5		
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C, V _{GS} =-20V / +20V		6	±20	μΑ
Drain-source on-resistance	R _{DS(on)}	V_{GS} =12V, I_{D} =20A, T_{J} =25°C		45	58	
		V _{GS} =12V, I _D =20A, T _J =125°C		67		mΩ
		V_{GS} =12V, I_{D} =20A, T_{J} =150°C		70		
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_{D} =10mA	4	5	6	V
Gate resistance	R_{G}	f=1MHz, open drain		4.5		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		Units		
			Min	Тур	Max	Units
Diode continuous forward current ¹	I _S	T _C < 120°C			18	Α
Diode pulse current ²	$I_{S,pulse}$	T _C =25°C			110	Α
Forward voltage	$V_{ ext{FSD}}$	V _{GS} =0V, I _F =10A, T _J =25°C		1.2	1.7	V
		V _{GS} =0V, I _F =10A, T _J =150°C		1.25		
Reverse recovery charge	Q _{rr}	V_R =400V, I_F =20A, V_{GS} =-5V, R_{G_EXT} =10 Ω di/dt=1380A/ μ s, T_J =25°C		185		nC
Reverse recovery time	t _{rr}			29		ns
Reverse recovery charge	Q _{rr}	V_R =400V, I_F =20A, V_{GS} =-5V, R_{G_EXT} =10 Ω		169		nC
Reverse recovery time	t _{rr}	di/dt=1380A/μs, Τ _J =150°C		28		ns













Typical Performance - Dynamic

Parameter	,	Test Conditions	Value			Units
Parameter		rest Conditions	Min	Тур	Max	UTILS
Input capacitance	C_{iss}	- V _{DS} =100V, V _{GS} =0V -		1500		
Output capacitance	C_{oss}	f=100kHz		200		pF
Reverse transfer capacitance	C_{rss}	1-100KH2		2.2		
Effective output capacitance, energy related	$C_{oss(er)}$	V_{DS} =0V to 400V, V_{GS} =0V		146		pF
Effective output capacitance, time related	$C_{oss(tr)}$	V_{DS} =0V to 400V, V_{GS} =0V		325		pF
C _{OSS} stored energy	E_{oss}	V_{DS} =400V, V_{GS} =0V		11.7		μJ
Total gate charge	Q_{G}	V _{DS} =400V, I _D =20A,		43		nC
Gate-drain charge	Q_{GD}	$V_{DS} = 400 \text{ V}, V_{D} = 20 \text{ A},$ $V_{GS} = -5 \text{ V to } 12 \text{ V}$		11		
Gate-source charge	Q_{GS}	VGS - 3V to 12 V		19		
Turn-on delay time	$t_{d(on)}$	V _{DS} =400V, I _D =20A, Gate		24		ns - ns - μJ
Rise time	t_r	Driver =-5V to +12V,		18		
Turn-off delay time	t _{d(off)}	$Turn-on R_{G,EXT}=8.5\Omega,$ $Turn-off R_{G,EXT}=22\Omega$ $Inductive Load,$ $FWD: same device with$ $V_{GS}=-5V, R_{G}=10\Omega,$ $T_{J}=25^{\circ}C$		44		
Fall time	t _f			9		
Turn-on energy	E _{ON}			144		
Turn-off energy	E _{OFF}			14		
Total switching energy	E _{TOTAL}			158		
Turn-on delay time	t _{d(on)}	V _{DS} =400V, I _D =20A, Gate		21		ns
Rise time	t_r	Driver =-5V to +12V,		15		
Turn-off delay time	t _{d(off)}	$\begin{array}{c} \text{Turn-on R}_{\text{G,EXT}} = 8.5\Omega, \\ \text{Turn-off R}_{\text{G,EXT}} = 22\Omega \\ \text{Inductive Load,} \\ \text{FWD: same device with} \\ \text{V}_{\text{GS}} = -5\text{V}, \text{R}_{\text{G}} = 10\Omega, \\ \end{array}$		47		
Fall time	t _f			8		
Turn-on energy	E _{ON}			118		
Turn-off energy	E _{OFF}			6		μЈ
Total switching energy	E _{TOTAL}	T _J =150°C		124		





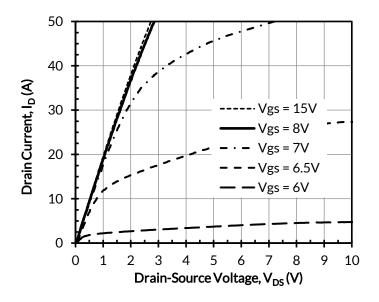








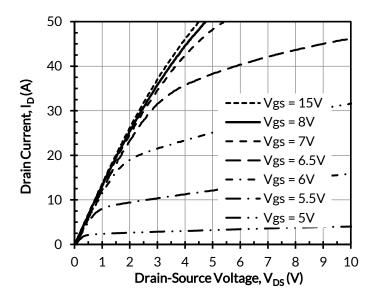
Typical Performance Diagrams



50 40 Drain Current, I_D (A) 30 Vgs = 15V 20 Vgs = 8V Vgs = 7V Vgs = 6.5V10 Vgs = 6V 0 2 0 1 5 10 Drain-Source Voltage, $V_{DS}(V)$

Figure 1. Typical output characteristics at T_J = - 55°C, tp < 250 μ s

Figure 2. Typical output characteristics at $T_J = 25$ °C, tp < 250 μ s



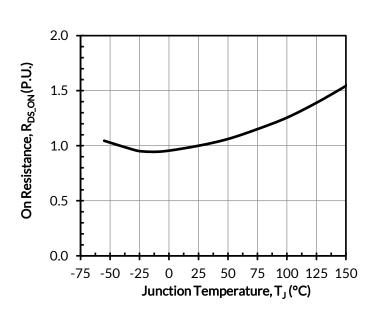


Figure 3. Typical output characteristics at T_J = 150°C, tp < 250 μ s

Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_{D} =20A



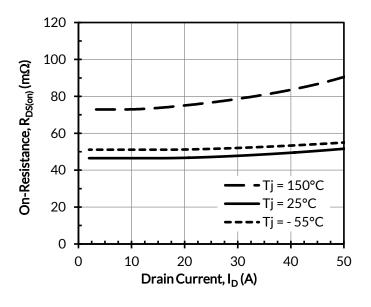








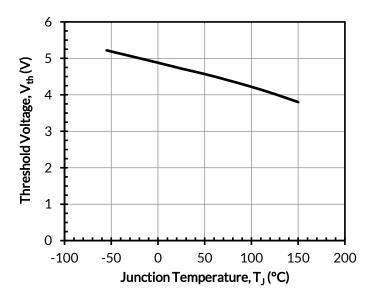




= -55°C Tj = 25°C Drain Current, I_D (A) **-** Tj = 150°C Gate-Source Voltage, $V_{GS}(V)$

Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at V_{DS} = 5V



See Notion 10 Gate Charge, Q_G (nC)

Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_{D} = 10mA

Figure 8. Typical gate charge at V_{DS} = 400V and I_{D} = 20A













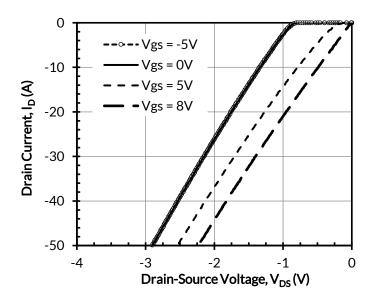


Figure 9. 3rd quadrant characteristics at T_J = -55°C

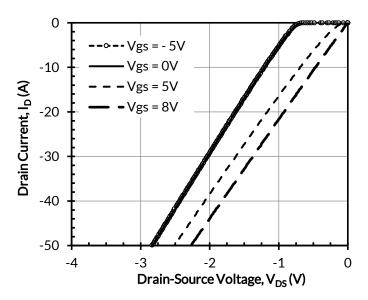


Figure 10. 3rd quadrant characteristics at $T_J = 25$ °C

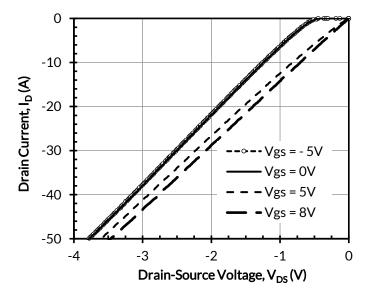


Figure 11. 3rd quadrant characteristics at $T_J = 150$ °C

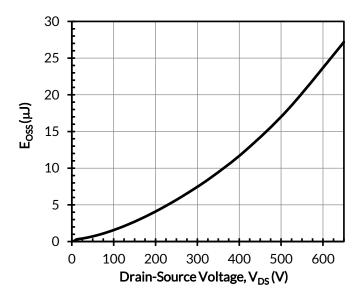


Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$













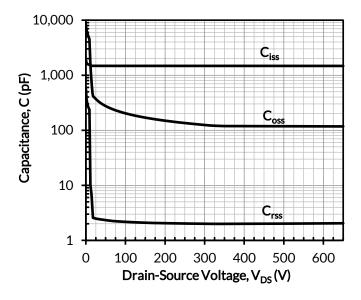
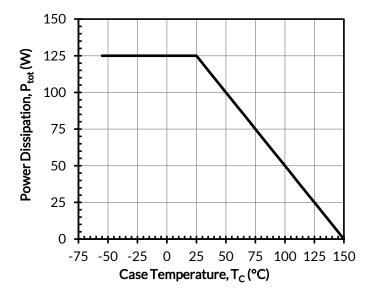


Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V

Figure 14. DC drain current derating



1 Thermal Impedance, Z_{θJC} (°C/W) 0.1 D = 0.5D = 0.3D = 0.1 -D = 0.050.01 ·· D = 0.02 -D = 0.01Single Pulse 0.001 1.E-05 1.E-04 1.E-03 1.E-02 1.E-01 1.E-06 Pulse Time, t_p (s)

Figure 15. Total power dissipation

Figure 16. Maximum transient thermal impedance













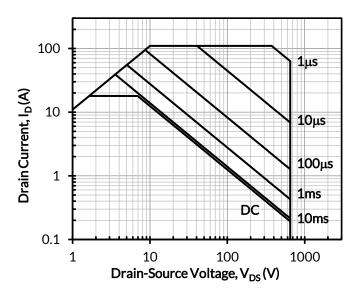


Figure 17. Safe operation area at $T_C = 25$ °C, D = 0, Parameter t_p

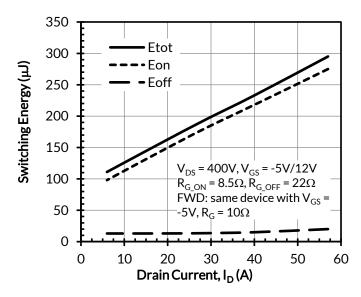


Figure 18. Clamped inductive switching energy vs. drain current at $T_J = 25$ °C

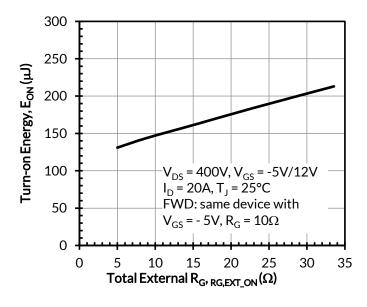


Figure 19. Clamped inductive switching turn-on energy vs. $R_{G,EXT\ ON}$

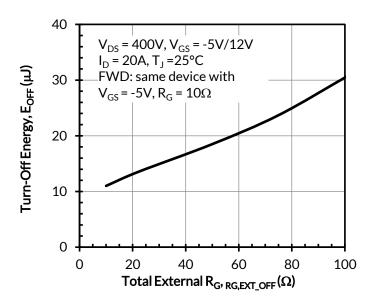


Figure 20. Clamped inductive switching turn-off energy vs. $R_{G,EXT\ OFF}$



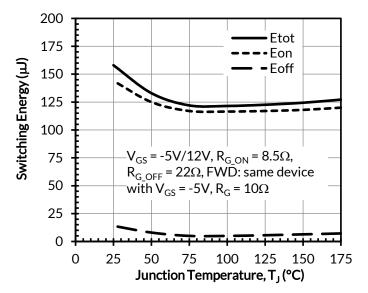












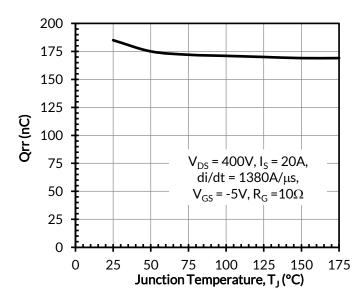


Figure 21. Clamped inductive switching energy vs. junction temperature at V_{DS} = 400V and I_D = 20A

Figure 22. Reverse recovery charge Qrr vs. junction temperature

Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_G) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see www.unitedsic.com.

Disclaimer

UnitedSiC reserves the right to change or modify any of the products and their inherent physical and technical specifications without prior notice. UnitedSiC assumes no responsibility or liability for any errors or inaccuracies within.

Information on all products and contained herein is intended for description only. No license, express or implied, to any intellectual property rights is granted within this document.

UnitedSiC assumes no liability whatsoever relating to the choice, selection or use of the UnitedSiC products and services described herein.

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

UnitedSiC:

UF3SC065040D8S